

MOS INTEGRATED CIRCUIT μ PD442000L-X

2M-BIT CMOS STATIC RAM 256K-WORD BY 8-BIT EXTENDED TEMPERATURE OPERATION

Description

The μ PD442000L-X is a high speed, low power, 2,097,152 bits (262,144 words by 8 bits) CMOS static RAM.

The μ PD442000L-X has two chip enable pins (/CE1, CE2) to extend the capacity. And battery backup is available.

B, C and D versions are low voltage versions.

★ The μ PD442000L-X is packed in 32-pin plastic TSOP (I) (8×13.4 mm) and (8×20 mm).

Features

• 262,144 words by 8 bits organization

★ Fast access time: 70, 85, 100, 120, 150, 180 ns (MAX.)

• Low voltage operation

(B version: Vcc = 2.7 to 3.6 V, C version: Vcc = 2.2 to 3.6 V, D version: Vcc = 1.8 to 3.6 V)

• Low Vcc data retention: 1.5 V (MIN.)

Operating ambient temperature : T_A = −25 to +85 °C

• Output Enable input for easy application

• Two Chip Enable inputs: /CE1, CE2

Part number	Access time	Operating supply	Operating ambient		Supply curre	nt
	ns (MAX.)	voltage	temperature	At operating	At standby	At data retention
		V	°C	mA (MAX.)	μA (MAX.)	μA (MAX.)
μPD442000L-BxxX	70 ^{Note} , 85, 100	2.7 to 3.6	-25 to +85	35	2	2
μPD442000L-CxxX	100, 120, 150	2.2 to 3.6		30		
μPD442000L-DxxX	150, 180	1.8 to 3.6		25		

Note Under development

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.

Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.



★ Ordering Information

Part number	Package	Access time	Operating	Operating	Remark
		ns (MAX.)	supply voltage	temperature	
			V	°C	
μPD442000LGU-B70X-9JH ^{Note}	32-pin Plastic TSOP (I)	70	2.7 to 3.6	-25 to +85	B version
μPD442000LGU-B85X-9JH	(8×13.4) (Normal bent)	85			
μPD442000LGU-B10X-9JH		100			
μ PD442000LGU-B70X-9KH $^{ exttt{Note}}$	32-pin Plastic TSOP (I)	70			
μPD442000LGU-B85X-9KH	(8×13.4) (Reverse bent)	85			
μPD442000LGU-B10X-9KH		100			
μ PD442000LGZ-B70X-KJH $^{ exttt{Note}}$	32-pin Plastic TSOP (I)	70			
μPD442000LGZ-B85X-KJH	(8×20) (Normal bent)	85			
μPD442000LGZ-B10X-KJH		100			
μPD442000LGZ-B70X-KKH Note	32-pin Plastic TSOP (I)	70			
μPD442000LGZ-B85X-KKH	(8×20) (Reverse bent)	85			
μPD442000LGZ-B10X-KKH		100			
μPD442000LGU-C10X-9JH	32-pin Plastic TSOP (I)	100	2.2 to 3.6		C version
μPD442000LGU-C12X-9JH	(8×13.4) (Normal bent)	120			
μPD442000LGU-C15X-9JH		150			
μPD442000LGU-C10X-9KH	32-pin Plastic TSOP (I)	100			
μPD442000LGU-C12X-9KH	(8×13.4) (Reverse bent)	120			
μPD442000LGU-C15X-9KH		150			
μPD442000LGZ-C10X-KJH	32-pin Plastic TSOP (I)	100			
μPD442000LGZ-C12X-KJH	(8×20) (Normal bent)	120			
μPD442000LGZ-C15X-KJH		150			
μPD442000LGZ-C10X-KKH	32-pin Plastic TSOP (I)	100			
μPD442000LGZ-C12X-KKH	(8×20) (Reverse bent)	120			
μPD442000LGZ-C15X-KKH		150			
μPD442000LGU-D15X-9JH	32-pin Plastic TSOP (I)	150	1.8 to 3.6		D version
μPD442000LGU-D18X-9JH	(8×13.4) (Normal bent)	180			
μPD442000LGU-D15X-9KH	32-pin Plastic TSOP (I)	150			
μPD442000LGU-D18X-9KH	(8×13.4) (Reverse bent)	180			
μPD442000LGZ-D15X-KJH	32-pin Plastic TSOP (I)	150			
μPD442000LGZ-D18X-KJH	(8×20) (Normal bent)	180			
μPD442000LGZ-D15X-KKH	32-pin Plastic TSOP (I)	150			
μPD442000LGZ-D18X-KKH	(8×20) (Reverse bent)	180			

Note Under development

Pin Configurations (Marking Side)

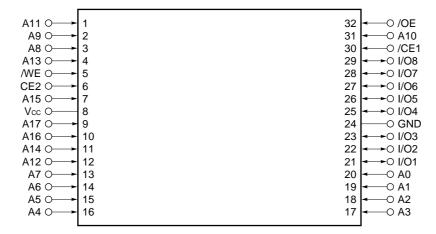
/xxx indicates active low signal.

32-pin Plastic TSOP (I) (8×13.4) (Normal bent)

[μPD442000LGU-BxxX-9JH] [μPD442000LGU-CxxX-9JH] [μPD442000LGU-DxxX-9JH]

32-pin Plastic TSOP (I) (8×20) (Normal bent)

[μ PD442000LGZ-BxxX-KJH] [μ PD442000LGZ-CxxX-KJH] [μ PD442000LGZ-DxxX-KJH]



A0 - A17 : Address inputs

I/O1 - I/O8 : Data inputs / outputs
/CE1, CE2 : Chip Enable 1, 2
/WE : Write Enable
/OE : Output Enable
Vcc : Power supply
GND : Ground

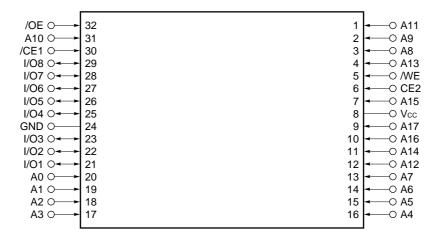
Remark Refer to Package Drawings for the 1-pin index mark.

32-pin Plastic TSOP (I) (8×13.4) (Reverse bent)

[μ PD442000LGU-BxxX-9KH] [μ PD442000LGU-CxxX-9KH] [μ PD442000LGU-DxxX-9KH]

32-pin Plastic TSOP (I) (8×20) (Reverse bent)

[μ PD442000LGZ-BxxX-KKH] [μ PD442000LGZ-CxxX-KKH] [μ PD442000LGZ-DxxX-KKH]



A0 - A17 : Address inputs

I/O1 - I/O8 : Data inputs / outputs

/CE1, CE2 : Chip Enable 1, 2

/WE : Write Enable

/OE : Output Enable

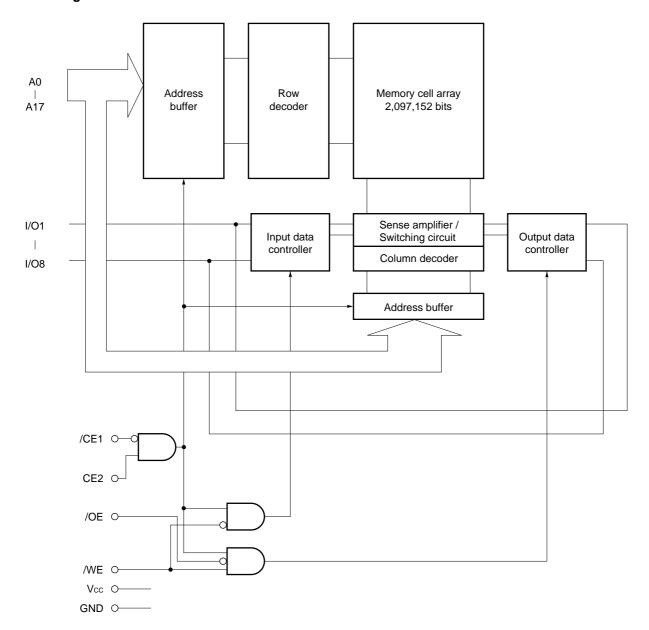
Vcc : Power supply

GND : Ground

Remark Refer to **Package Drawings** for the 1-pin index mark.



Block Diagram



Truth Table

/CE1	CE2	/OE	/WE	Mode	I/O	Supply current
Н	×	×	×	Not selected	High impedance	IsB
×	L	×	×	Not selected	High impedance	
L	Н	Н	Н	Output disable	High impedance	ICCA
L	Н	L	Н	Read	D оит	
L	Н	×	L	Write	Din	

Remark ×: VIH or VIL



Electrical Specifications

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Supply voltage	Vcc		-0.5 Note to +4.6	V
Input / Output voltage	VT		−0.5 Note to Vcc+0.5	V
Operating ambient temperature	TA		-25 to +85	°C
Storage temperature	T _{stg}		-55 to +125	°C

Note -3.0 V (MIN.) (Pulse width: 30 ns)

Caution Exposing the device to stress above those listed in Absolute Maximum Rating could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	μPD4420	00L-BxxX	μPD4420	00L-CxxX μPD44200		00L-DxxX	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Supply voltage	Vcc		2.7	3.6	2.2	3.6	1.8	3.6	V
High level input voltage	VIH	2.7 V ≤ Vcc ≤ 3.6 V	2.4	Vcc+0.5	2.4	Vcc+0.5	2.4	Vcc+0.5	V
		2.2 V ≤ Vcc < 2.7 V	-	-	2.0	Vcc+0.5	2.0	Vcc+0.5	
		1.8 V ≤ Vcc < 2.2 V					1.6	Vcc+0.5	
Low level input voltage	VIL		-0.3 Note	+0.5	-0.3 Note	+0.3	-0.3 Note	+0.2	V
Operating ambient temperature	TA		-25	+85	-25	+85	-25	+85	°C

Note -1.5 V (MIN.) (Pulse width: 30 ns)

Capacitance ($T_A = 25$ °C, f = 1 MHz)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	Cin	Vin = 0 V			8	pF
Input / Output capacitance	C _{I/O}	V ₁ /O = 0 V			10	pF

Remarks 1. VIN: Input voltage

Vi/o: Input / Output voltage

2. These parameters are periodically sampled and not 100% tested.



DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

Parameter	Symbol	Test condit	ion	μPD4	42000L	-BxxX	μPD4	42000L	-CxxX	μPD4	42000L	-DxxX	Unit
				MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Input leakage current	lu	Vin = 0 V to Vcc		-1.0		+1.0	-1.0		+1.0	-1.0		+1.0	μΑ
I/O leakage	ILO	V _{I/O} = 0 V to V _{CC} , /CE	1 = Vін or	-1.0		+1.0	-1.0		+1.0	-1.0		+1.0	μΑ
current		CE2 = VIL or /WE = VI	ıL or /OE = Vıн										
Operating	ICCA1	/CE1 = VIL, CE2 = VIH	,		30	35		25	30		20	25	mA
supply current		Minimum cycle time,	Vcc ≤ 2.7 V		_	_		20	25		15	20	
		I _{1/O} = 0 mA	Vcc ≤ 2.2 V		_	_		_	_		10	15	
	Icca2	/CE1 = VIL, CE2 = VIH	,			10			10			10	
		I _{1/0} = 0 mA	Vcc ≤ 2.7 V			_			8			8	
			Vcc ≤ 2.2 V			_			_			5	
	Іссаз	/CE1 ≤ 0.2 V, CE2 ≥ \	Vcc - 0.2 V,			8			8			8	
		Cycle = 1 MHz, I _{I/O} = 0	0 mA,										
		V1L ≤ 0.2 V,	Vcc ≤ 2.7 V			_			6			6	
		V _{IH} ≥ V _{CC} − 0.2 V	Vcc ≤ 2.2 V			_			_			5	
Standby	Isa	/CE1 = VIH or CE2 = \	/ IL			0.3			0.3			0.3	mA
supply current	I _{SB1}	/CE1 ≥ Vcc - 0.2 V,			0.1	2		0.1	2		0.1	2	μΑ
		CE2 ≥ Vcc - 0.2 V	Vcc ≤ 2.7 V		_	_		0.08	2		0.08	2	
			Vcc ≤ 2.2 V		_	_		_	_		0.05	1.5	
	I _{SB2}	CE2 ≤ 0.2 V			0.1	2		0.1	2		0.1	2	
			Vcc ≤ 2.7 V		_	_		0.08	2		0.08	2	
			Vcc ≤ 2.2 V		_	_		_	-		0.05	1.5	
High level	Vон	Iон = -0.5 mA		2.4			2.4			2.4			٧
output voltage			Vcc ≤ 2.7 V	_			1.8			1.8			
			Vcc ≤ 2.2 V	_			_			1.5			
Low level	Vol	IoL = 1.0 mA				0.4			0.4			0.4	٧
output voltage													

Remarks 1. VIN: Input voltage

Vi/o: Input / Output voltage

2. These DC characteristics are in common regardless of package types and access time.

Data Sheet M12509EJ7V0DS 7



AC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

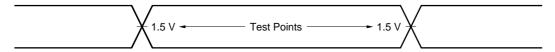
AC Test Conditions

[μ PD442000L-B70X, μ PD442000L-B85X, μ PD442000L-B10X]

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform

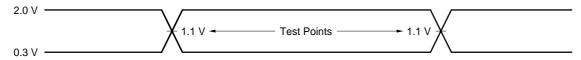


Output Load

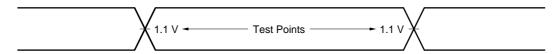
1TTL + 50 pF

[μ PD442000L-C10X, μ PD442000L-C12X, μ PD442000L-C15X]

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform

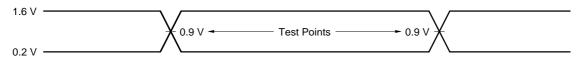


Output Load

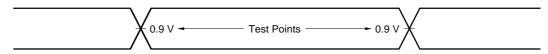
1TTL + 50 pF

\star [μPD442000L-D15X, μPD442000L-D18X]

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform



Output Load

1TTL + 50 pF



Read Cycle (1/3) (B version)

Parameter	Symbol	μPD4420	00L-B70X	μPD4420	00L-B85X	μPD4420	00L-B10X	Unit	Condition
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read cycle time	t RC	70		85		100		ns	
Address access time	taa		70		85		100	ns	Note 1
/CE1 access time	t co1		70		85		100	ns	
CE2 access time	tco2		70		85		100	ns	
/OE to output valid	toe		35		40		50	ns	
Output hold from address change	tон	10		10		10		ns	
/CE1 to output in low impedance	t _{LZ1}	10		10		10		ns	Note 2
CE2 to output in low impedance	tLZ2	10		10		10		ns	
/OE to output in low impedance	tolz	5		5		5		ns	
/CE1 to output in high impedance	t _{HZ1}		25		30		35	ns	
CE2 to output in high impedance	t _{HZ2}		25		30		35	ns	
/OE to output in high impedance	tонz		25		30		35	ns	

Notes 1. The output load is 1TTL + 50 pF.

2. The output load is 1TTL + 5 pF.

Remark These AC characteristics are in common regardless of package types.

Read Cycle (2/3) (C version)

Parameter	Symbol	μPD4420	00L-C10X	μPD4420	00L-C12X	μPD4420	00L-C15X	Unit	Condition
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read cycle time	t RC	100		120		150		ns	
Address access time	t AA		100		120		150	ns	Note 1
/CE1 access time	t co1		100		120		150	ns	
CE2 access time	t CO2		100		120		150	ns	
/OE to output valid	toe		50		60		70	ns	
Output hold from address change	tон	10		10		10		ns	
/CE1 to output in low impedance	t _{LZ1}	10		10		10		ns	Note 2
CE2 to output in low impedance	tLZ2	10		10		10		ns	
/OE to output in low impedance	tolz	5		5		5		ns	
/CE1 to output in high impedance	t _{HZ1}		35		40		45	ns	
CE2 to output in high impedance	t _{HZ2}		35		40		45	ns	
/OE to output in high impedance	tонz		35		40		45	ns	

Notes 1. The output load is 1TTL + 50 pF.

2. The output load is 1TTL + 5 pF.

Remark These AC characteristics are in common regardless of package types.



★ Read Cycle (3/3) (D version)

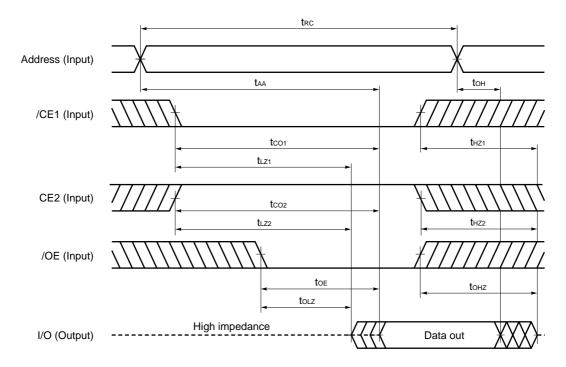
Parameter	Symbol	μPD4420	00L-D15X	μPD4420	00L-D18X	Unit	Condition
		MIN.	MAX.	MIN.	MAX.		
Read cycle time	trc	150		180		ns	
Address access time	t AA		150		180	ns	Note 1
/CE1 access time	t co1		150		180	ns	
CE2 access time	tco2		150		180	ns	
/OE to output valid	toe		70		80	ns	
Output hold from address change	tон	10		10		ns	
/CE1 to output in low impedance	t _{LZ1}	10		10		ns	Note 2
CE2 to output in low impedance	t _{LZ2}	10		10		ns	
/OE to output in low impedance	tolz	5		5		ns	
/CE1 to output in high impedance	t _{HZ1}		45		50	ns	
CE2 to output in high impedance	t _{HZ2}		45		50	ns	
/OE to output in high impedance	tонz		45		50	ns	

Notes 1. The output load is 1TTL + 50 pF.

2. The output load is 1TTL + 5 pF.

Remark These AC characteristics are in common regardless of package types.

Read Cycle Timing Chart



Remark In read cycle, /WE should be fixed to high level.



Write Cycle (1/3) (B version)

Parameter	Symbol	μPD4420	00L-B70X	μPD4420	00L-B85X	μPD4420	00L-B10X	Unit	Condition
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Write cycle time	twc	70		85		100		ns	
/CE1 to end of write	tcw1	55		70		80		ns	
CE2 to end of write	tcw2	55		70		80		ns	
Address valid to end of write	taw	55		70		80		ns	
Address setup time	t AS	0		0		0		ns	
Write pulse width	twp	50		60		60		ns	
Write recovery time	twr	0		0		0		ns	
Data valid to end of write	tow	30		35		40		ns	
Data hold time	tон	0		0		0		ns	
/WE to output in high impedance	twнz		25		30		35	ns	Note
Output active from end of write	tow	5		5		5		ns	

Note The output load is 1TTL + 5 pF.

Remark These AC characteristics are in common regardless of package types.

Write Cycle (2/3) (C version)

Parameter	Symbol	μPD4420	00L-C10X	μPD4420	00L-C12X	μPD4420	00L-C15X	Unit	Condition
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Write cycle time	twc	100		120		150		ns	
/CE1 to end of write	tcw1	80		100		120		ns	
CE2 to end of write	tcw2	80		100		120		ns	
Address valid to end of write	taw	80		100		120		ns	
Address setup time	tas	0		0		0		ns	
Write pulse width	twp	60		80		100		ns	
Write recovery time	twr	0		0		0		ns	
Data valid to end of write	tow	40		50		60		ns	
Data hold time	tон	0		0		0		ns	
/WE to output in high impedance	twнz		35		40		50	ns	Note
Output active from end of write	tow	5		5		5		ns	

Note The output load is 1TTL + 5 pF.

Remark These AC characteristics are in common regardless of package types.

Data Sheet M12509EJ7V0DS 11



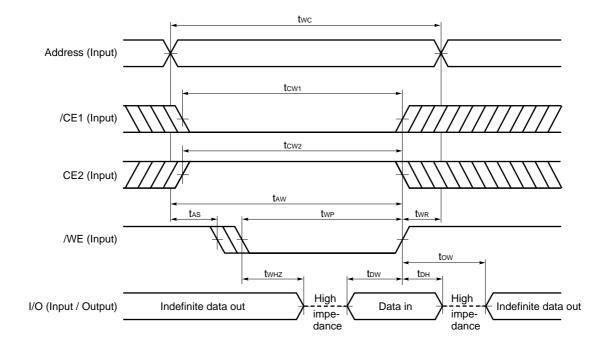
★ Write Cycle (3/3) (D version)

Parameter	Symbol	μPD442000L-D15X		μPD442000L-D18X		Unit	Condition
		MIN.	MAX.	MIN.	MAX.		
Write cycle time	twc	150		180		ns	
/CE1 to end of write	tcw1	120		150		ns	
CE2 to end of write	tcw2	120		150		ns	
Address valid to end of write	taw	120		150		ns	
Address setup time	tas	0		0		ns	
Write pulse width	twp	100		120		ns	
Write recovery time	twr	0		0		ns	
Data valid to end of write	tow	60		75		ns	
Data hold time	tон	0		0		ns	
/WE to output in high impedance	twnz		50		60	ns	Note
Output active from end of write	tow	5		5		ns	

Note The output load is 1TTL + 5 pF.

Remark These AC characteristics are in common regardless of package types.

Write Cycle Timing Chart 1 (/WE Controlled)



Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.

2. When I/O pins are in the output state, do not apply to the I/O pins signals that are opposite in phase with output signals.

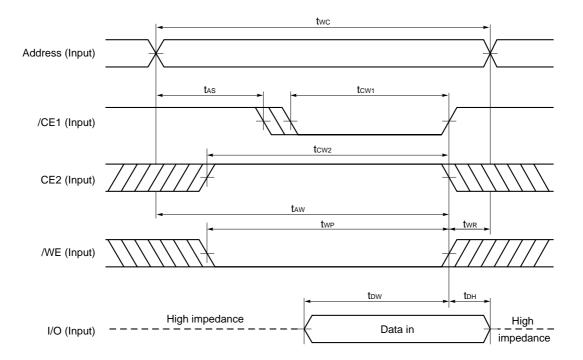
Remarks 1. Write operation is done during the overlap time of a low level /CE1, /WE, and a high level CE2.

- 2. If /CE1 changes to low level at the same time or after the change of /WE to low level, or if CE2 changes to high level at the same time or after the change of /WE to low level, the I/O pins will remain high impedance state.
- 3. When /WE is at low level, the I/O pins are always high impedance. When /WE is at high level, read operation is executed. Therefore /OE should be at high level to make the I/O pins high impedance.

Data Sheet M12509EJ7V0DS 13



Write Cycle Timing Chart 2 (/CE1 Controlled)

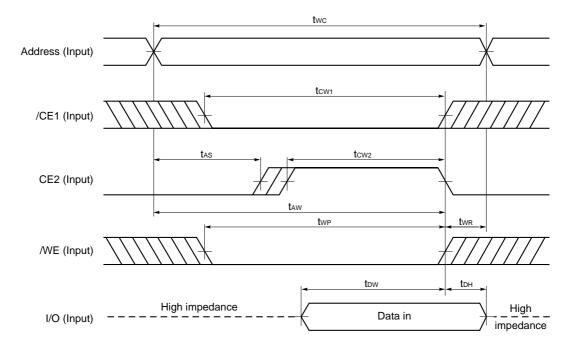


Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.

2. When I/O pins are in the output state, do not apply to the I/O pins signals that are opposite in phase with output signals.

Remark Write operation is done during the overlap time of a low level /CE1, /WE, and a high level CE2.

Write Cycle Timing Chart 3 (CE2 Controlled)



Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.

2. When I/O pins are in the output state, do not apply to the I/O pins signals that are opposite in phase with output signals.

Remark Write operation is done during the overlap time of a low level /CE1, /WE, and a high level CE2.



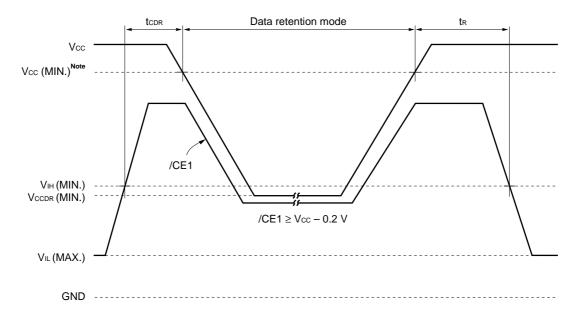
Low Vcc Data Retention Characteristics (T_A = -25 to +85 °C)

Parameter	Symbol	Test Condition	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	Vccdr1	/CE1 ≥ Vcc – 0.2 V, CE2 ≥ Vcc – 0.2 V	1.5		3.6	V
	Vccdr2	CE2 ≤ 0.2 V	1.5		3.6	
Data retention supply current	ICCDR1	Vcc = 3.0 V, /CE1 ≥ Vcc – 0.2 V,		0.1	2	μΑ
		$CE2 \ge Vcc - 0.2 \text{ V or } CE2 \le 0.2 \text{ V}$				
	ICCDR2	Vcc = 3.0 V, CE2 ≤ 0.2 V		0.1	2	
Chip deselection to data retention mode	tcdr		0			ns
Operation recovery time	tR		trc Note			ns

Note tRC: Read cycle time.

Data Retention Timing Chart

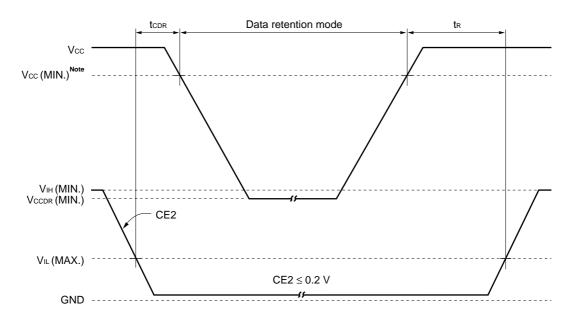
(1) /CE1 Controlled



Note B version: 2.7 V, C version: 2.2 V, D version: 1.8 V

Remark On the data retention mode by controlling /CE1, the input level of CE2 must be \geq Vcc - 0.2 V or \leq 0.2 V. The other pins (Address, I/O, /WE, /OE) can be in high impedance state.

(2) CE2 Controlled



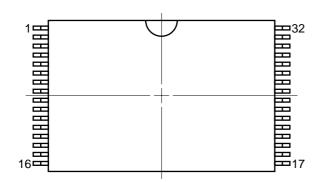
Note B version: 2.7 V, C version: 2.2 V, D version: 1.8 V

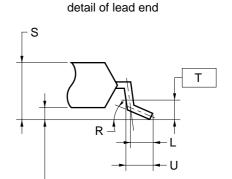
Remark On the data retention mode by controlling CE2, the other pins (/CE1, Address, I/O, /WE, /OE) can be in high impedance state.



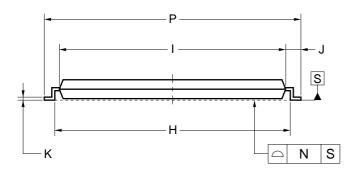
Package Drawings

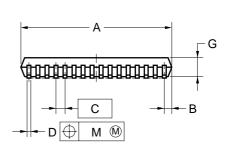
* 32-PIN PLASTIC TSOP(I) (8x13.4)





Q



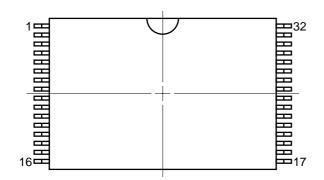


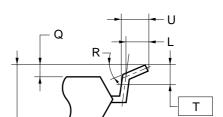
- 1. Each lead centerline is located within 0.08 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash : $8.3 \ \text{mm} \ \text{MAX.}$)

ITEM	MILLIMETERS
Α	8.0±0.1
В	0.45 MAX.
С	0.5 (T.P.)
D	0.22±0.05
G	1.0±0.05
Н	12.4±0.2
I	11.8±0.1
J	0.8±0.2
K	$0.145^{+0.025}_{-0.015}$
L	0.5
М	0.08
N	0.08
Р	13.4±0.2
Q	0.1±0.05
R	3°+5°
S	1.2 MAX.
Т	0.25
U	0.6±0.15

P32GU-50-9JH-2

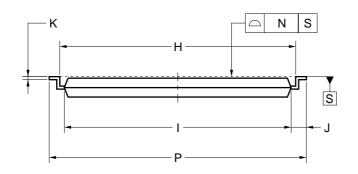
* 32-PIN PLASTIC TSOP(I) (8x13.4)

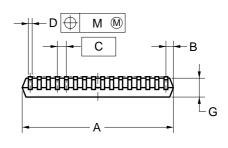




S

detail of lead end



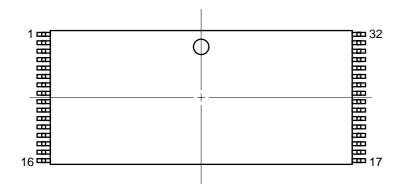


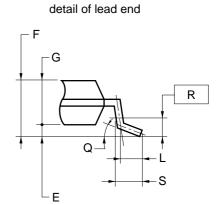
- Each lead centerline is located within 0.08 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash : 8.3 mm MAX.)

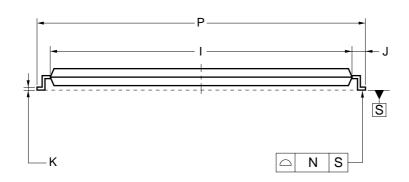
ITEM	MILLIMETERS
Α	8.0±0.1
В	0.45 MAX.
С	0.5 (T.P.)
D	0.22±0.05
G	1.0±0.05
Н	12.4±0.2
I	11.8±0.1
J	0.8±0.2
K	$0.145^{+0.025}_{-0.015}$
L	0.5
М	0.08
N	0.08
Р	13.4±0.2
Q	0.1±0.05
R	3°+5° -3°
S	1.2 MAX.
Т	0.25
U	0.6±0.15

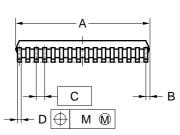
P32GU-50-9KH-2

* 32-PIN PLASTIC TSOP(I) (8x20)







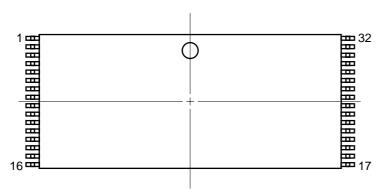


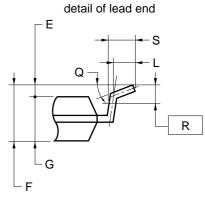
- Each lead centerline is located within 0.10 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash: 8.3 mm MAX.)

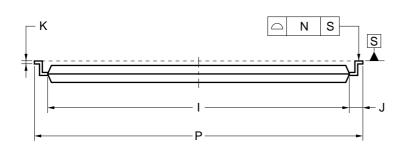
ITEM	MILLIMETERS
Α	8.0±0.1
В	0.45 MAX.
С	0.5 (T.P.)
D	0.22±0.05
Е	0.1±0.05
F	1.2 MAX.
G	0.97±0.08
I	18.4±0.1
J	0.8±0.2
K	0.145±0.05
L	0.5
M	0.10
N	0.10
Р	20.0±0.2
Q	3°+5°
R	0.25
S	0.60±0.15

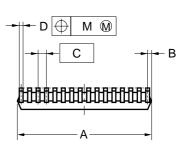
S32GZ-50-KJH1-2

* 32-PIN PLASTIC TSOP(I) (8x20)









- Each lead centerline is located within 0.10 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash: 8.3 mm MAX.)

ITEM	MILLIMETERS
Α	8.0±0.1
В	0.45 MAX.
С	0.5 (T.P.)
D	0.22±0.05
Е	0.1±0.05
F	1.2 MAX.
G	0.97±0.08
I	18.4±0.1
J	0.8±0.2
K	0.145±0.05
L	0.5
М	0.10
N	0.10
P	20.0±0.2
Q	3°+5°
R	0.25
S	0.60±0.15
	22227 50 1/1/14 2

S32GZ-50-KKH1-2



Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the μ PD442000L-X.

★ Types of Surface Mount Device

μPD442000LGU-BxxX-9JH : 32-pin Plastic TSOP (I) (8×13.4) (Normal bent) μPD442000LGU-CxxX-9JH : 32-pin Plastic TSOP (I) (8×13.4) (Normal bent) μ PD442000LGU-DxxX-9JH : 32-pin Plastic TSOP (I) (8×13.4) (Normal bent) μPD442000LGU-BxxX-9KH : 32-pin Plastic TSOP (I) (8×13.4) (Reverse bent) μ PD442000LGU-CxxX-9KH : 32-pin Plastic TSOP (I) (8×13.4) (Reverse bent) μ PD442000LGU-DxxX-9KH : 32-pin Plastic TSOP (I) (8×13.4) (Reverse bent) μPD442000LGZ-BxxX-KJH : 32-pin Plastic TSOP (I) (8×20) (Normal bent) μPD442000LGZ-CxxX-KJH : 32-pin Plastic TSOP (I) (8×20) (Normal bent) μPD442000LGZ-DxxX-KJH : 32-pin Plastic TSOP (I) (8×20) (Normal bent) μ PD442000LGZ-BxxX-KKH : 32-pin Plastic TSOP (I) (8×20) (Reverse bent) : 32-pin Plastic TSOP (I) (8×20) (Reverse bent) μPD442000LGZ-CxxX-KKH μ PD442000LGZ-DxxX-KKH : 32-pin Plastic TSOP (I) (8×20) (Reverse bent)

NOTES FOR CMOS DEVICES

(1) PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

2 HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

3 STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

- The information in this document is current as of December, 2000. The information is subject to change without notice. For actual design-in, refer to the latest publications of NEC's data sheets or data books, etc., for the most up-to-date specifications of NEC semiconductor products. Not all products and/or types are available in every country. Please check with an NEC sales representative for availability and additional information.
- No part of this document may be copied or reproduced in any form or by any means without prior written consent of NEC. NEC assumes no responsibility for any errors that may appear in this document.
- NEC does not assume any liability for infringement of patents, copyrights or other intellectual property rights of
 third parties by or arising from the use of NEC semiconductor products listed in this document or any other
 liability arising from the use of such products. No license, express, implied or otherwise, is granted under any
 patents, copyrights or other intellectual property rights of NEC or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative
 purposes in semiconductor product operation and application examples. The incorporation of these
 circuits, software and information in the design of customer's equipment shall be done under the full
 responsibility of customer. NEC assumes no responsibility for any losses incurred by customers or third
 parties arising from the use of these circuits, software and information.
- While NEC endeavours to enhance the quality, reliability and safety of NEC semiconductor products, customers
 agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize
 risks of damage to property or injury (including death) to persons arising from defects in NEC
 semiconductor products, customers must incorporate sufficient safety measures in their design, such as
 redundancy, fire-containment, and anti-failure features.
- NEC semiconductor products are classified into the following three quality grades:
 - "Standard", "Special" and "Specific". The "Specific" quality grade applies only to semiconductor products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of a semiconductor product depend on its quality grade, as indicated below. Customers must check the quality grade of each semiconductor product before using it in a particular application.
 - "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots
 - "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
 - "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC semiconductor products is "Standard" unless otherwise expressly specified in NEC's data sheets or data books, etc. If customers wish to use NEC semiconductor products in applications not intended by NEC, they must contact an NEC sales representative in advance to determine NEC's willingness to support a given application.

(Note)

- (1) "NEC" as used in this statement means NEC Corporation and also includes its majority-owned subsidiaries.
- (2) "NEC semiconductor products" means any semiconductor product developed or manufactured by or for NEC (as defined above).

M8E 00.4